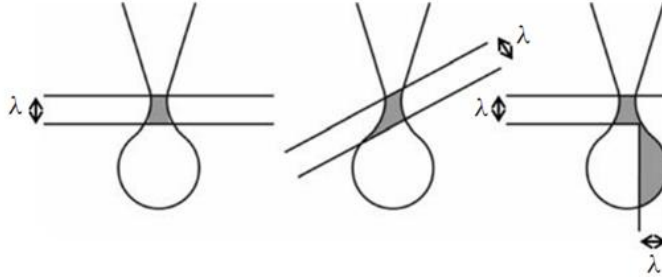
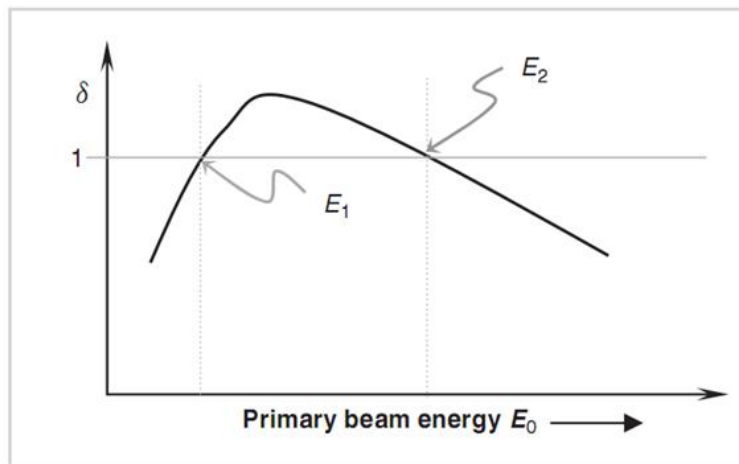
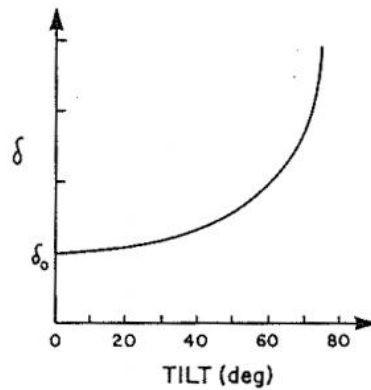


δ (similar as η) has a dependence on the angle of tilt of the sample.



Schematic illustration of the tilt angle dependence of secondary electron emission. Only those electrons created within a distance λ of the surface are able to escape (shaded area). As the surface is tilted, a greater proportion of the interaction volume is exposed. Emission at edges is particularly high.



Schematic plot of total yield illustrating the increase in yield as the primary beam energy is reduced.